2460 SourceMeter® SMU Instrument

Datasheet



KEITHLEY

The 2460 High Current SourceMeter® Source Measure Unit (SMU) Instrument brings advanced Touch, Test, Invent® technology right to your fingertips. It combines an innovative graphical user interface (GUI) with capacitive touchscreen technology to make testing intuitive and minimize the learning curve to help engineers and scientists learn faster, work smarter, and invent easier. With its 7A DC and pulse current capability, the 2460 is optimized for characterizing and testing high power materials, devices, and modules such as silicon carbide (SiC), gallium nitride (GaN), DC-DC converters, power MOSFETs, solar cells and panels, LEDs and lighting systems, electrochemical cells and batteries, and much more. These new capabilities, combined with Keithley's decades of expertise in developing high precision, high accuracy SMU instruments, will make the 2460 a "go-to instrument" for high current applications in the lab and in the rack for years to come.

Key Features

- One tightly coupled instrument that combines capabilities from analyzers, curve tracers, and I-V systems at a fraction of their cost
- Wide coverage up to 105 V, 7 A DC/7 A pulse, 100 W max.
- Five-inch, high resolution capacitive touchscreen GUI
- 0.012% basic measure accuracy with 6½-digit resolution
- Source and sink (4-quadrant) operation
- Four "Quickset" modes for fast setup and measurements
- Context-sensitive help function
- Front panel input banana jacks; rear panel input mass termination screw connections
- 2460 SCPI and TSP® scripting programming modes
- Front-panel USB 2.0 memory I/O port for transferring data, test scripts, or test configurations



2460 main home screen.



Learn Faster, Work Smarter, Invent Easier

The 2460 features a five-inch, full-color, high resolution touchscreen that supports intuitive operation, helps operators become familiar with the instrument quickly, and optimizes overall speed and productivity. A simple icon-based menu structure reduces the number of steps required to configure a test by as much as 50 percent and eliminates the cumbersome multi-layer menu structures typically used on soft-key instruments. Built-in, context-sensitive help supports intuitive operation and minimizes the need to review a separate manual. These capabilities, combined with the 2460's high versatility, simplify its operation in both basic and advanced measurement applications, regardless of the user's previous experience in working with SMU instruments.

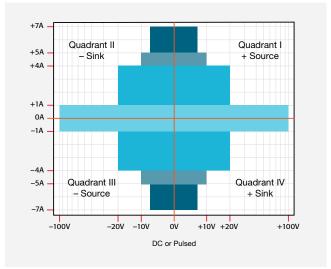


2460 icon-based menu.

All-in-One SMU Instrument

The 2460, built on the fourth generation of the award-winning SourceMeter SMU platform, leverages the proven capabilities of previously introduced high current SMU instruments from Keithley, including the 2420, 2425, and 2440. It offers a highly flexible, four-quadrant voltage and current source/load coupled with precision voltage and current measurements. This all-in-one instrument gives you the capabilies of a:

- Precision power supply with V and I readback
- True current source
- Digital multimeter (DCV, DCI, ohms, and power with 6½-digit resolution)
- · Precision electronic load
- Trigger controller



2460 power envelope.

Comparison Table: 2420, 2425, and 2440 with 2460

2420/2425/2440	2460
Max Voltage: 60 V/100 V/40 V	Max Voltage: 100 V
Max Current: 3 A/3 A/5 A	Max Current: 7 A
DC Power: 60 W/100 W/50 W	DC Power: 100 W
Wideband Noise: 10 mV rms typ.	Wideband Noise: 2 mV rms typ.
Sweep Types: Linear, Log, Custom, Source-Memory	Sweep Types: Linear, Log, Dual Linear, Dual Log, Custom
5000 Point Reading Buffer	>250,000 Point Reading Buffer
>2000 Readings/second	>3000 Readings/second
SCPI Programming	SCPI Programming + TSP Scripting
GPIB, RS-232	GPIB, USB, Ethernet (LXI)
Front/Rear Banana Jacks	Front: Banana Jacks. Rear: Mass Screw Terminal Connection



2460 front panel with high-resolution, capacitive touchscreen.

Ease of Use Beyond the Touchscreen

In addition to its advanced touchscreen, the 2460's front panel offers a variety of features that enhance its speed, user-friendliness, and learnability, including a USB 2.0 memory I/O port, a HELP key, a rotary navigation/control knob, a front/rear input selector button, and banana jacks for basic bench applications. The USB 2.0 memory port simplifies storing test results and instrument configurations, uploading test scripts into the instrument, and installing system upgrades. All front-panel buttons are backlit to enhance visibility in low-light environments.

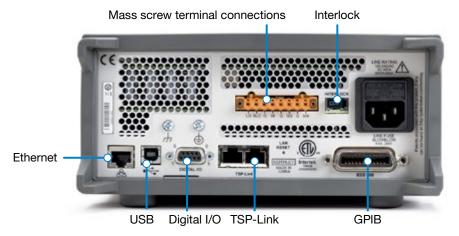
Four "Quickset" modes simplify instrument setup. With one touch, the instrument can be quickly configured for various operating modes without the need to configure the instrument indirectly for this operation.

Function SIMV, SIMR, SYML, SYM

One-touch Quickset modes speed measurement setups $\$ nd minimize the time to measurements.

Comprehensive Built-in Connectivity

Rear panel access to rear-input mass termination connector, remote control interfaces (GPIB, USB 2.0, and LXI/Ethernet), D-sub 9-pin digital I/O port (for internal/ external trigger signals and handler control), instrument interlock control, and TSP-Link® jacks make it simple to configure multiple instrument test solutions and eliminate the need to invest in additional adapter accessories.



Rear panel connections are optimized for signal integrity and speed system setup

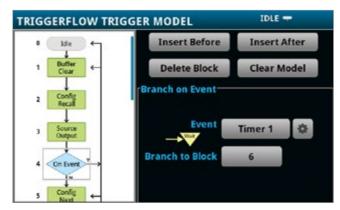
Convert Raw Data to Information

A full graphical plotting window converts raw data and displays it immediately as useful information, such as semiconductor I-V curves and voltammograms. Using the 2460's Sheet view, test data can also be displayed in tabular form. The instrument supports exporting data to a spreadsheet for further analysis, dramatically improving productivity for research, benchtop testing, device qualification, and debugging.

TriggerFlow® Building Blocks for Instrument Control and Execution

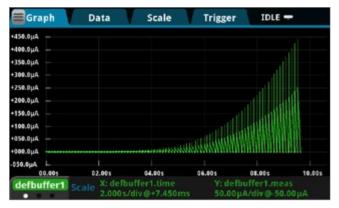
The 2460 incorporates Keithley's TriggerFlow triggering system, which provides user control over instrument execution. TriggerFlow diagrams are created in much the same way that flow charts are developed, using four fundamental building block types:

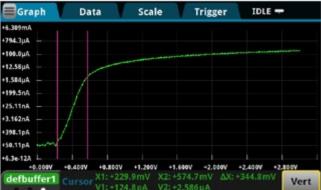
- Wait Waits for an event to occur before the flow continues
- Branch Branches when a condition has been satisfied
- Action Initiates an action in the instrument, for example, measure, source, delay, set digital I/O, etc.
- Notify Notifies other equipment that an event has occurred

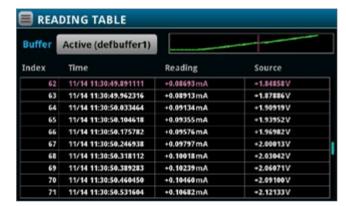


TriggerFlow building blocks allow creating triggering models that range from very simple to highly complex.

A TriggerFlow model using a combination of these building blocks can be created from the front panel or by sending remote commands. With the TriggerFlow system, users can build triggering models from very simple to complex with up to 63 block levels. The 2460 also includes basic triggering functions, including immediate, timer, and manual triggering.







Built-in data display, charting, and spreadsheet export functions simplify converting test results into useful information.

Typical Applications

Ideal for current/voltage characterization and functional test of a wide range of modern electronic devices:

- Power semiconductors and materials
 - SiC, GaN
 - IBGTs
 - Power MOSFETs
 - Thyristors
- Power devices
 - Telecom power management chipsets
 - DC-DC converters
- Electrochemistry
 - Battery charge/ discharge cycling
 - Cyclic voltammetry
 - Electro-deposition
- Energy generation
 - Solar cells
 - Batteries
- Efficient energy consumption
 - LEDs/AMOLEDs
 - Automotive modules
 - Power management modules









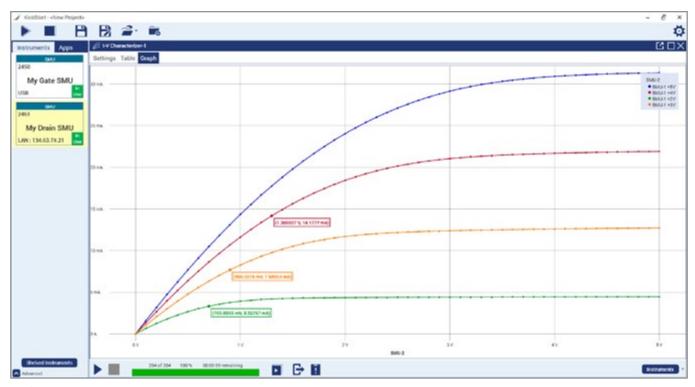


Unmatched System Integration and Programming Flexibility

When a 2460 is configured into a multi-channel I-V test system, its embedded Test Script Processor (TSP®) allows it to run test scripts, so users can create powerful measurement applications with significantly reduced development times. TSP technology also offers channel expansion without a mainframe. Keithley's TSP-Link® channel expansion bus, which uses a 100 Base T Ethernet cable, can connect multiple 2460s and other TSP instruments such as Keithley's 2450 SourceMeter SMU Instruments, Series 2600B System SourceMeter SMU instruments, and Series 3700A Switch/Multimeter systems in a master-subordinate configuration that operates as one integrated system. The TSP-Link expansion bus supports up to 32 units per GPIB or IP address, making it easy to scale a system to fit an application's particular requirements. The 2460 also includes a SCPI programming mode that takes advantage of all of the instrument's capabilities.

Parallel Test Capability

The TSP technology in the 2460 supports testing multiple devices in parallel to meet the needs of device research, advanced semiconductor lab applications, and even high throughput production test. This parallel testing capability allows each instrument in the system to run its own complete test sequence, creating a fully multi-threaded test environment. The number of tests that can be run in parallel on a 2460 can be as high as the number of instruments in the system.



KickStart start-up software lets users be ready to make measurements in minutes.

Instrument Control Start-up Software

KickStart instrument control/start-up software enables users to start making measurements in minutes without programming. In most cases, users merely need to make some quick measurements, graph the data, and store the data to disk for later analysis in software environments such as Excel. KickStart offers:

- Configure and control up to four SMU instruments for DC or Pulsed I-V test in either the same app, same project, or a combination of the two.
- Create tests by mixing any of these SMU instruments: 2400 Graphical Series, 2400 Standard Series (DC only), 2600B Series, 2651A, 2657A, and 6430 SourceMeter® SMU (DC only) instruments.
- Differentiate SMU instrument channels and their measurement data using labels that are relevant to your device or module.
- Native X-Y graphing, panning, and zooming; screenshot capturing of graphs.
- Spreadsheet/tabular viewing of data; export data for further analysis.
- · Annotating of tests; save test setups.
- GPIB, USB 2.0, Ethernet compliance.

Optional Apps Tailored for your Characterization Needs

The 2460 is an excellent tool to define nearly any DC test you choose for characterizing materials, electronic devices and modules. For more specific needs, Keithley offers on-instrument software apps that alter the 2460's behavior, fitting your instrument to your needs. These apps can be installed directly to your 2460 by connecting to Keithley's KickStart instrument control software and opening the relevant app in KickStart.

I-V Tracer App

Curve tracing analysis is a critical task for many users in the semiconductor development supply chain. Engineers and technicians both hold the traditional curve tracer as the simplest, fastest method for generating characteristic I-V curves on a device. They are heavily used by engineers in failure analysis and incoming inspection to qualify parts, identify counterfeit devices, and to quickly identify the location of a failure on damaged devices. SMUs have typically been limited to predefined sweeps with longer set up times than curve tracers — until I-V Tracer.

Keithley's I-V Tracer app leverages the touchscreen and front-panel knob of the 2460 to allow precise, live control over the SMU output while viewing I-V results of 2 terminal

devices. At each individual output level current and voltage are measured and plotted. The small footprint of the SMU enables portable bench top use, reserving high power (kW) traditional curve tracers for special cases. The power envelope of the 2460 allows it to comfortably operate in the low power range of traditional curve tracers like the Tektronix 576 and Tektronix 370A, while offering enhanced low current measurements.



I-V Tracer home screen

Once installed, I-V Tracer exists on the SMU itself, meaning I-V tracer can be used wherever your SMU can go, without a continuous remote connection. It can also integrate with KickStart to enable simple data collection and comparison on the PC, simplifying the preparation of reports used in failure analysis or teaching labs at colleges and universities.

I-V Tracer capabilities with the 2460:

- Use the full power envelope of the 2460 (max 100 V or 7 A)
- Trace by sourcing voltage or current, positive or negative
- 2 or 4-wire sense
- Compare mode for verifying against a reference device
- Reading table view to see exact measurements
- Easily copy curves and settings to your PC with KickStart

Simplified Programming with Ready-to-Use Instrument Drivers

For those who prefer to create their own customized application software, native National Instruments LabVIEW® drivers, as well as IVI-C and IVI-COM drivers are available at www.tek.com/keithley.

Specifications

Voltage Specifications 1, 2

			Source			Measu	ire ³
Range	Max. Current	`		Noise (RMS) (<10 Hz)	Resolution	Input Resistance	Accuracy (23° ± 5°C) 1 Year ±(% rdg. + volts)
200.0000 mV	7.35 A	5 μV	0.015% + 200 μV	1 µV	100 nV	>10 GΩ	0.012% + 200 μV
2.000000 V	7.35 A	50 μV	0.015% + 300 μV	10 μV	1 μV	>10 GΩ	0.012% + 300 μV
7.000000 V	7.35 A	250 μV	0.015% + 2.4 mV	100 μV	1 μV	>10 GΩ	0.015% + 1 mV
10.00000 V	5.25 A	250 μV	0.015% + 2.4 mV	100 μV	10 μV	>10 GΩ	0.015% + 1 mV
20.00000 V	4.20 A	500 μV	0.015% + 2.4 mV	100 μV	10 μV	>10 GΩ	0.015% + 1 mV
100.0000 V	1.05 A	2.5 mV	0.015% + 15 mV	1 mV	100 μV	>10 GΩ	0.015% + 5 mV

Current Specifications 1, 2, 5

		Source				Measu	ıre ³
Range	Max. Voltage	Accuracy (23° ±5°C) ⁴ 1 Year Resolution ±(% setting + amps)		Noise (RMS) (<10 Hz)	Resolution 4	Voltage Burden ⁶	Accuracy (23° ±5°C) 1 Year ±(% rdg. + amps)
1.000000 μΑ	105 V	50 pA	0.025% + 1 nA	40 pA	1 pA	<100 μV	0.025% + 700 pA
10.00000 μΑ	105 V	500 pA	0.025% + 1.5 nA	40 pA	10 pA	<100 μV	0.025% + 1 nA
100.0000 μΑ	105 V	5 nA	0.020% + 15 nA	100 pA	100 pA	<100 μV	0.020% + 10 nA
1.000000 mA	105 V	50 nA	0.020% + 150 nA	1 nA	1 nA	<100 μV	0.020% + 100 nA
10.00000 mA	105 V	500 nA	0.020% + 1.5 μA	10 nA	10 nA	<100 μV	0.020% + 1 µA
100.0000 mA	105 V	5 μΑ	0.020% + 15 μA	100 nA	100 nA	<100 μV	0.020% + 10 μA
1.000000 A	105 V	50 μΑ	0.050% + 750 μA	5 μΑ	1 μΑ	<100 μV	0.050% + 500 μΑ
4.000000 A	21 V	250 μΑ	0.100% + 3 mA	25 μΑ	1 μΑ	<100 μV	0.100% + 2.5 mA
5.000000 A	10.5 V	250 μΑ	0.100% + 3 mA	25 μΑ	1 μΑ	<100 μV	0.100% + 2.5 mA
7.000000 A	7.35 V	500 μΑ	0.150% + 6 mA	125 µA	1 μΑ	<100 μV	0.150% + 5 mA

Temperature Coefficient (0°-18°C and 28°-50°C)

 $\pm (0.10 \times accuracy specification)/^{\circ}C.$

Notes

- 1. Speed = 1 PLC.
 2. All specifications are guaranteed with output ON.
 3. Accuracies apply to 2- and 4-wire mode when properly zeroed.
 4. 6.5-digit measure resolution.
 5. Accuracy specifications guaranteed when using 2460-KIT screw terminal accessory.
 6. Four-wire mode.

Resistance Measurement Accuracy (Local or Remote Sense) 1, 2, 3

Range	Default Resolution 4	Default Test Current	Normal Accuracy (23°C ±5°C) 1 Year, ±(% rdg. + ohms)	Enhanced Accuracy ⁵ (23°C ±5°C) 1 Year, ±(% rdg. + ohms)
<2.000000 Ω ⁶	1 μΩ	User defined	Source I_{ACC} + Meas. V_{ACC}	Meas. I _{ACC} + Meas. V _{ACC}
20.00000 Ω	10 μΩ	100 mA	$0.05\% + 0.003 \Omega$	0.04% + 0.001 Ω
200.0000 Ω	100 μΩ	10 mA	0.05% + 0.03 Ω	0.04% + 0.01 Ω
2.000000 kΩ	1 mΩ	1 mA	$0.05\% + 0.3 \Omega$	0.04% + 0.1 Ω
20.00000 kΩ	10 mΩ	100 μΑ	0.05% + 3 Ω	0.04% + 1 Ω
200.0000 kΩ	100 mΩ	10 μΑ	0.05% + 30 Ω	0.05% + 10 Ω
2.000000 MΩ	1 Ω	10 μΑ	0.06% + 100 Ω	0.06% + 50 Ω
20.00000 MΩ	10 Ω	1 μΑ	0.14% + 1000 Ω	0.12% + 500 Ω
>20.0000 MΩ ⁶	_	User defined	Source I _{ACC} + Meas. V _{ACC}	Meas. I _{ACC} + Meas. V _{ACC}

Temperature Coefficient (0°-18°C and 28°-50°C)	$\pm (0.10 \times accuracy specification)/°C.$
Source Current, Measure Resistance Mode	Total uncertainty = Isource accuracy + Vmeasure accuracy (4-wire remote sense).
Source Voltage, Measure Resistance Mode	Total uncertainty = Vsource accuracy + Imeasure accuracy (4-wire remote sense).
Guard Output Impedance	$0.5~\Omega$ (DC) in ohms mode.

Notes

- 1. Speed = 1 PLC.
- 2. All specifications are guaranteed with output ON.
- 3. Accuracies apply to 2- and 4-wire mode when properly zeroed.
- 4. 6.5-digit measure resolution.
- 5. Source readback enabled. Offset compensation ON.
- 6. Source current, measure resistance or source voltage, measure resistance only.

Supplemental Characteristics

Overrange 105% of range, source and measure. Regulation Voltage: Line: 0.01% of range. Load: 0.01% of range + 100 μV. Current: Line: 0.01% of range. Load: 0.01% of range + 100 pA. Source Limits Voltage Source Current Limit: Bipolar current limit set with single value. Min. 10% of range. V-Limit / I-Limit Accuracy Add 0.3% of setting and $\pm 0.02\%$ of reading to base specification. Overshoot Voltage Source: <0.1% typical (full scale step, resistive load, 20 V range, 10 mA I-Limit. Current Source: <0.1% typical (1 mA step, $R_{Load} = 10 k\Omega$, 20 V range). Range Change Overshoot Overshoot into a fully resistive 100 kΩ load, 10 Hz to 20 MHz BW, adjacent ranges: <250 mV typical Output Settling Time Time required to reach 0.1% of final value after command is processed and output slew, 20 V range 100 mA I-Limit: <200 μs typical.	Supplemental Charac	teristics
Isource: ±7.35 A (≤7 V range), ±5.25 A (≤10 V range), ±4.2 A (≤20 V range), ±1.05 mA (≤100 V range) Overrange 105% of range, source and measure. Regulation Voltage: Line: 0.01% of range. Load: 0.01% of range + 100 μV. Current: Line: 0.01% of range. Load: 0.01% of range + 100 μA. Source Limits Voltage Source Current Limit: Bipolar current limit set with single value. Min. 10% of range. Current Source Voltage Limit: Bipolar voltage limit set with single value. Min. 10% of range. V-Limit / I-Limit Accuracy Add 0.3% of setting and ±0.02% of reading to base specification. Overshoot Voltage Source: <0.1% typical (full scale step, resistive load, 20 V range, 10 mA I-Limit. Current Source: <0.1% typical (1 mA step, R _{Load} = 10 kΩ, 20 V range). Range Change Overshoot Overshoot into a fully resistive 100 kΩ load, 10 Hz to 20 MHz BW, adjacent ranges: <250 mV typical Output Settling Time Time required to reach 0.1% of final value after command is processed and output slew, 20 V range 100 mA I-Limit: <200 μs typical. Maximum Slew Rate 1 V per μs, 100 V range, 100 mA limit into a 20 kΩ load (typical). 0.6 V per μs, 20 V range, 100 mA lia 20 kΩ load (typical). Over Voltage Protection User selectable values, 5% ±0.5 V tolerance. Factory default = none. Voltage Source Noise 10Hz-20MHz (RMS): <4.5 mV typical into a resistive load. Common Mode Voltage 250V DC.	Max. Output Power	100 W, four-quadrant source or sink operation.
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Current Source Voltage Limit: Bipolar voltage limit set with single value. Min. 10% of range. V-Limit / I-Limit Accuracy Add 0.3% of setting and $\pm 0.02\%$ of reading to base specification. Overshoot Voltage Source: <0.1% typical (full scale step, resistive load, 20 V range, 10 mA I-Limit. Current Source: <0.1% typical (1 mA step, $R_{Load} = 10 \text{ k}\Omega$, 20 V range). Range Change Overshoot Overshoot into a fully resistive 100 kΩ load, 10 Hz to 20 MHz BW, adjacent ranges: <250 mV typical	Regulation	· · · · · · · · · · · · · · · · · · ·
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Common Mode Voltage 250V DC.	Over Voltage Protection	User selectable values, 5% ±0.5 V tolerance. Factory default = none.
	Voltage Source Noise	10Hz-20MHz (RMS): <4.5 mV typical into a resistive load.
Common Mode Isolation >1G Ω , <1000 pF.	Common Mode Voltage	250V DC.
	Common Mode Isolation	>1G Ω , <1000 pF.

Noise Rejection (typical)

NPLC	NMRR	CMRR
0.01	_	60 dB
0.1	_	60 dB
1	60 dB	100 dB

Load Impedance	Normal Mode: 20 nF typical. High Capacitance Mode: Stable into 50 μF typical. High-C mode valid for ≥100 μA ranges.		
Max. Voltage Drop Between Force and Sense Terminals	5 V.		
Max. Sense Lead Resistance	1 M Ω for rated accuracy.		
Sense Input Impedance	>10 GΩ.		
Guard Offset Voltage	<300 μV, typical		

System Measurement Speeds 1

Reading Rates (readings/second) typical for 60 Hz (50 Hz), script (TSP®) programmed

NPLC	Trigger Origin	Measure to Memory	Measure to GPIB/USB/LAN	Source-Measure to Memory	Source-Measure to GPIB/USB/LAN
0.01	Internal	3050 (2800)	2800 (2500)	1700 (1600)	1650 (1550)
0.01	External	2300 (2100)	2150 (2000)	1650 (1550)	1600 (1450)
0.1	Internal	540 (460)	530 (450)	470 (410)	470 (400)
0.1	External	500 (420)	500 (420)	460 (390)	450 (350)
1.00	Internal	59 (49)	59 (49)	58 (48)	58 (48)
1.00	External	58 (48)	58 (48)	57 (48)	57 (46)

Reading Rates (readings/second) typical for 60 Hz (50 Hz), SCPI programmed

NPLC	Trigger Origin	Measure to Memory	Measure to GPIB/USB/LAN	Source-Measure to Memory	Source-Measure to GPIB/USB/LAN
0.01	Internal	3000 (2800)	3000 (2790)	1700 (1600)	1550 (1500)
0.01	External	2330 (2150)	2330 (2150)	1650 (1550)	1500 (1450)
0.1	Internal	540 (460)	540 (460)	470 (410)	460 (400)
0.1	External	510 (430)	510 (430)	470 (400)	460 (390)
1.00	Internal	59 (49)	59 (49)	58 (48)	58 (48)
1.00	External	58 (49)	58 (49)	58 (48)	58 (48)

Notes

1. Reading rates applicable for voltage or current measurements, autozero off, autorange off, filter off, binary reading format, and source readback off.

General Characteristics (default mode unless specified)

Factory Default Standard Power-Up	SCPI Mode.
Source Output Modes	Fixed DC Level, Memory/Configuration List (mixed function), Sweep (linear and logarithmic), Sweep (dual linear and dual logarithmic.
Memory Buffer	>250,000 readings. Includes selected measured value(s) and time stamp.
Real-Time Clock	Lithium battery backup (3 yr. + battery life).
Remote Interfaces	
GPIB	IEEE-488.1 compliant. Supports IEEE-488.2 common commands and status model topology.
USB Device (rear panel, type B)	2.0 Full Speed USBTMC.
USB Host (front panel, type A)	USB 2.0, support for flash drives, FAT32.
Ethernet: RJ-45 (10/100BT)	
Digital I/O Interface	
Lines	6 Input/Output user defined for digital I/O or triggering.
Connector	9-pin female D.
Input Signal Levels	0.7 V (maximum logic low), 3.7 V (minimum logic high).
Input Voltage Limits	-0.25 V (Abs. minimum), +5.25 V (Abs. maximum).
Maximum Source Current	+2.0 mA @ >2.7 V (per pin).
Maximum Sink Current	−50 mA @ 0.7 V (per pin, solid-state fuse protected).
5 V Power Supply Pin	Limited to 500 mA @ >4 V (solid-state fuse protected).
Handler	User definable Start of Test, End of Test, 4 category bits.
Programmability	SCPI or TSP command sets.
TSP Mode	Embedded Test Script Processor (TSP) accessible from any host interface.
IP Configuration	Static or DHCP.
Expansion Interface	The TSP-Link expansion interface allows TSP enabled instruments to trigger and communicate with each other.
LXI Compliance	1.5 LXI Device Specification 2016.
Display	5 inch capacitive touch, color TFT WVGA (800×480) with LED backlight.
Input Signal Connections	Front: Banana. Rear: Mass termination screw terminal.
Interlock	Active High Input.
Cooling	Forced air, variable speed.
Over Temperature Protection	Internally sensed temperature overload puts unit in standby mode.
Power Supply	100 V to 240 V RMS, 50-60 Hz (automatically detected at power up).
VA Rating	350 volt-amps max.
Altitude	Maximum 2000 meters above sea level.
EMC	Conforms to European Union EMC Directive.
Safety	Compliance with CE and NRTL listed to UL61010-1 and UL61010-2-30. Conforms with European Union Low Voltage Directive.
Vibration	MIL-PRF-28800F Class 3 Random.
Warm-Up	1 hour to rated accuracies.

Dimensions	With bumpers and handle: 106 mm high \times 255 mm wide \times 425 mm deep (4.18 in \times 10.05 in \times 16.75 in). Without bumpers and handle: 88 mm high \times 213 mm wide \times 403 mm deep (3.46 in \times 8.39 in \times 15.87 in).
Weight	With bumpers and handle: 4.75 kg (10.5 lbs.). Without bumpers and handle: 4.35 kg (9.6 lbs.).
Environment	Operating: 0° to 50°C, 70% R.H. up to 35°C. Derate 3% R.H./°C, 35° to 50°C. Storage: –25°C to 65°C.
Accessories Supplied	Test Leads, Mating Mass Terminated Screw Connector, USB Cable, Ethernet/TSP Cable, Interlock Adapter, Power Cord, QuickStart Guide.

Ordering Information

2460 100 V, 7 A, 100 W SourceMeter Instrument

Supplied Accessories

2460-KIT	Rear Panel Mating Mass Terminated Screw Connector
8608	High Performance Test Leads
USB-B-1	USB Cable, Type A to Type B, 1m (3.3 ft)
CS-1616-3	Safety Interlock Mating Connector
17469460X	TSP-Link/Ethernet Cable
	Documentation available at www.tektronix.com
	2460 QuickStart Guide
	Test Script Builder Software (available at www.tektronix.com)
	KickStart Startup Software (available at www.tektronix.com)
	LabVIEW and IVI Drivers (available at www.tektronix.com)

Available Accessories

Test Leads and Probes		
5805	Kelvin (4-Wire) Spring-Loaded Probes	
5808	Low Cost Single-pin Kelvin Probe Set	
8606	High Performance Modular Probe Kit	

Cables, Connectors, Adapters	
2460-BAN	Screw Terminal Connector to Banana Cable
2460-KIT	Mating Mass Termination Connector
CS-1616-3	Safety Interlock Mating Connector

Communication Interfaces & Cables	
7007-1	Shielded GPIB Cable, 1 m (3.3 ft)
KPCI-488LPA	IEEE-488 Interface for PCI Bus
KUSB-488B	IEEE-488 USB-to-GPIB Interface Adapter

Rack Mount Kits		
4299-8	Single Fixed Rack Mount Kit	
4299-9	Dual Fixed Rack Mount Kit	
Software Options		
I-V Tracer	Graphical SMU Curve Tracer Software	
Kickstart	Instrument Control Software	
ACS Basic Edition	Semiconductor Parametric Test Software for Component and Discrete Devices	

Available Services

2460-3Y-EW	1 Year Factory Warranty extended to 3 years from date of shipment
2460-5Y-EW	1 Year Factory Warranty extended to 5 years from date of shipment
C/2460-3Y-17025	KeithleyCare® 3 Year ISO 17025 Calibration Plan
C/2460-3Y-DATA	KeithleyCare 3 Year Calibration w/Data Plan
C/2460-3Y-STD	KeithleyCare 3 Year Std. Calibration Plan
C/2460-5Y-17025	KeithleyCare 5 Year ISO 17025 Calibration Plan
C/2460-5Y-DATA	KeithleyCare 5 Year Calibration w/Data Plan
C/2460-5Y-STD	KeithleyCare 5 Year Std. Calibration Plan
C/NEW DATA	Calibration Data for New Units
C/NEW DATA ISO	ISO-17025 Calibration Data for New Units

Warranty Information

Warranty Summary	This section summarizes the warranties of the 2460. FFor complete warranty information, refer to the Tektronix warranty page at www.tek.com/service/warranties/warranty-2 . Any portion of the product that is not manufactured by Keithley is not covered by this warranty and Keithley will have no duty to enforce any other manufacturer's warranties.
Hardware Warranty	Keithley Instruments, Inc. warrants the Keithley manufactured portion of the hardware for a period of one year from defects in materials or workmanship; provided that such defect has not been caused by use of the Keithley hardware which is not in accordance with the hardware instructions. The warranty does not apply upon any modification of Keithley hardware made by the customer or operation of the hardware outside the environmental specifications.
Software Warranty	Keithley warrants for the Keithley produced portion of the software or firmware will conform in all material respects with the published specifications for a period of ninety (90) days; provided the software is used on the product for which it is intended in accordance with the software instructions. Keithley does not warrant that operation of the software will be uninterrupted or error-free, or that the software will be adequate for the customer's intended application. The warranty does not apply upon any modification of the software made by the customer.



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